



IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Inventors: Kenichiro SHINOI, et al.

Application No.: 10/542,611

Filed: July 18, 2005

For: ACCURACY MEASUREMENT APPARATUS AND ACCURACY
MEASUREMENT METHOD FOR CHANNEL QUALITY REPORT

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner of Patents
Washington, DC 20231

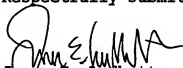
Dear Sir:

Pursuant to Rules 56 and 99, Applicants hereby call the attention of the Patent Office to the art listed on the attached Form PTO 1449. All of these references were cited in a Supplementary European Search Report dated April 12, 2007.

Applicants present this art so that the Patent Office may, in the first instance, determine any relevancy thereof to the presently claimed invention, see Beckman Instruments, Inc. v. Chemtronics, Inc., 439 F.2d 1369, 1380, 165 USPQ 355, 364 (5th Cir. 1970). Also see Patent Office Rules 104 and 106. Applicants respectfully request that this art be expressly considered during the prosecution of this application and made of record herein and

appear among the "References Cited" on any patent to issue herefrom.

Respectfully submitted,



James E. Ledbetter

Registration No. 28,732

Date: July 9, 2007

JEL/ejw

ATTORNEY DOCKET NO. L9289.05161

STEVENS, DAVIS, MILLER & MOSHER, L.L.P.

1615 L STREET, NW, Suite 850

WASHINGTON, DC 20043-4387

Telephone: (202) 785-0100

Facsimile: (202) 408-5200

